


<b>Search Notes</b> 	<b>Application/Control No.</b> 10540024	<b>Applicant(s)/Patent Under Reexamination</b> ONODA ET AL.
	<b>Examiner</b> STEVEN KIM	<b>Art Unit</b> 3685

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
see attached East search notes		s.k.

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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